

TITLE: METHOD AND APPARATUS FOR MEASURING WAVEFRONT  
ABERRATIONS

ABSTRACT OF THE DISCLOSURE

An apparatus and method for measuring wavefront aberrations. The apparatus comprises a reflecting device for reflecting selected portions of the wavefront, an imaging device for capturing information related to the selected portions, and a processor for calculating aberrations of the wavefront from the captured information. The method comprises reflecting selected portions of a wavefront onto the imaging device, capturing information related to the selected portions, and processing the captured information to derive the aberrations.